

7

Referências

- [1] R.Kiessling et.al. Acta Chemical Scandinava, 4, 209 (1950)
- [2] M.V. Frandsen, W.S.Williams, J.Hard.Mater. 4, 113 (1993)
- [3] B.Moukoff et al. Materials Letters 60, 1433 (2006)
- [4] L.Wang, R.J.Arsenault, Metall. Trans. A, 22, 3013 (1991)
- [5] M.Kornamnn and R. Funk, Aluminium, 53, 249 (1977)
- [6] C.Feldman, *et al.*, J. Less-Common Met., 79, 221 (1981)
- [7] R.G.Munro, J.Res.Natl.Inst.Stand.Technol. 105, 709 (2000)
- [8] <http://www.azom.com/details.asp?ArticleID=492>
- [9] Mattias Berger, Development and Tribological Characterisation of Magnetron Sputtered TiB₂ and Cr/CrN Coatings, Uppsala University 2001.
- [10] J.Pelleg, Physica B 381, 118 (2006)
- [11] M-L.Wu, X.Lin, V.P.Dravid, Y-W.Chung, M-S.Wong, and W.D.Sproul, Tribol.Lett. 5, 131 (1998)
- [12] H.Karner, J.Laimer, H.Störi, Surf.Coat.Technol. 39-40, 293 (1989)
- [13] R.Gilmore *et al.*, Surf.Coat.Technol. 116-119, 1127 (1999)
- [14] M.A.Nicolet, Thin Solid Films, 52, 415 (1978)
- [15] J.R.Shappirio *et al.* J.Vac.Sci.Technol. A, 3, 2255 (1985)
- [16] A.W.Mullendore et al. Thin Solid Films, 63, 243 (1979)
- [17] A.E.Kaloyeros et al. Phys.Rev.B 38, 7333 (1988)
- [18] J.P.Riviere, P.Guesdon, J.DeLafond, and M.F.Denanot, Thin Solid Films, 204, 151 (1991)
- [19] Y.Yang, Z.Z., X.Wang, X.Lin, J.Han, and J.S.Yoon, Surf.Coat.Technol. 84, 404 (1996)
- [20] G.Sade, and J.Pelleg, Appl.Surf.Sci. 91, 263 (1995)
- [21] R.Wiedemman and H.Oettel, Surf.Eng. 14, 299 (1998)
- [22] J.G.Ryan, S.Roberts, G.J.Slusser, and E.D.Adams, Thin Solid Films 153, 329 (1987)
- [23] T.Shikama, Y.Sakai, M.Fukutomi, and M.Okada, Thin Solid Films 156, 287 (1988)

- [24] T.Larsson, H-O.Blom, S.Berg, and M.Östling, *Thin Solid Films* 172, 133 (1989)
- [25] H-O.Blom, T.Larsson, S.Berg, and M.Östling, *J.Vac.Sci.Technol. A* 7, 162 (1989)
- [26] B.Matthes, E.Broszeit, and K.H.Kloos, *Surf.Coat.Technol.* 44,721 (1990)
- [27] W.Herr, B.Matthes, E.Broszeit, and K.H.Kloos, *Mater.Sci.Eng. A* 140, 616 (1991)
- [28] J.Chen, and J.A.Barnard, *Mater.Sci.Eng. A* 191, 233 (1995)
- [29] H.Deng, J.Chen, R.B.Inturi, and J.A.Barnard, *Surf.Coat.Technol.* 76-77, 609 (1995)
- [30] P.Losbichler and C.Mitterer, *Surf.Coat.Technol.* 97, 567 (1997)
- [31] R.Wiedemman, H.Oettel, and M.Jarencz, *Surf.Coat.Technol.* 97, 313 (1997)
- [32] E.Kelesoglu and C.Mitterer, *Surf.Coat.Technol.* 98, 1483 (1998)
- [33] M-L.Wu, Z.Yang, Y-W.Chung, M-S.Wong, and W.D.Sproul, *ASME J.Tribol.* 120, 179 (1998)
- [34] M.Berger, M.Larsson, and S.Hogmark, *Surf.Coat.Technol.* 124, 253 (2000)
- [35] X.Wang, P.J.Martin, and T.J.Kinder, *Surf.Coat.Technol.* 78, 37 (1996)
- [36] B.Todorovic, T.Jokic, Z.Rakocevic, Z.Markovic, B.Gakovic, and T.Nenadovic, *Thin Solid Films* 300, 272 (1997)
- [37] W.Herr and E.Broszeit, *Surf.Coat.Technol.* 97, 335 (1997)
- [38] <http://www.kennametal.de>
- [39] T.P.Mollart, J.Haupt, R.Gilmore, W.Gissler, *Surf.Coat.Technol.* 86/87, 231 (1996)
- [40] David.A.Glocker, S.Ismat Shah, *Handbook of Thin Film Process Technology*, 98/1 Reactive Sputtering, Institute of Physics Publishing, Bristol and Philadelphia (1998)
- [41] Mitsuharu Konuma, *Film Deposition by Plasma Techniques*, Springer-Verlag Telos, 1992
- [42] W.R.Grove, *Phil.Trans.Roy.Soc.London A* 142, 87 (1852)
- [43] R.W.Berry, *US Patent* 2, 993, 266 (1961)
- [44] W.D.Westwood *Physics of Thin Films*, Vol.14, eds. M.H.Francombe and J.L.Vossen, Academic Press, New York (1989)
- [45] M.Ohring, *Materials Science of Thin Films*, Second Edition (1991)
- [46] J.A.Thornton, *Ann. Rev. Mater. Sci.* 7, 239 (1977)

- [47] W.K.Chu, J.W.Mayer, M.A.Nicolet, Backscattering Spectrometry, Academic Press, New York (1978)
- [48] L.R.Doolittle, Nuclear Inst.Meth.Phys.Res.B 9, 344 (1985)
- [49] L.R.Doolittle, Nuclear Inst.Meth.Phys.Res.B 15,227 (1986)
- [50] D.Briggs and M.P.Seah, Practical Surface Analysis by Auger and X-ray photoelectron spectroscopy. John Wiley & Sons Ltd. (1982)
- [51] J.F.Watts, J.Wolstenholme, An Introduction to Surface Analysis by XPS and AES. John Wiley & Sons Ltd. (2003)
- [52] G.C.Stoney, Proc.R.Soc.London, Ser.A 32, 172 (1909)
- [53] J.W.Zou, K.Schmidt, K.Reichelt, B.Strizker, J.Vac.Sci.Technol. A 6, 3103 (1988)
- [54] M.E.Schroder, Journal of Colloid and Interface Science, 213, 602 (1999)
- [55] T.Young, Philos.Trans.R.Soc.London 95, 65 (1805)
- [56] M.E.H.Maia da Costa, Tese de Doutorado, Departamento de Física, PUC-Rio (2005)
- [57] G.Binning, C.F.Quate and C.Gerber, Phys.Rev.Lett.56, 930 (1986)
- [58] G.V.Dedkov, Phys.Stat.Sol.(a) 179, 3 (2000)
- [59] R.W.Carpick, Chem.Rev. 97, 1163 (1997)
- [60] E.Liu, B.Blanpain, J.P.Celis, Wear 192, 141 (1996)
- [61] J.M.Neumeister, W.A.Ducker, Rev.Sci.Instrum. 65, 2527 (1994)
- [62] R.R.M.Zamora, Tese de Doutorado, Departamento de Física, PUC-Rio (2005)
- [63] M.Berger, L.Karlsson, M.Larsson, S.Hogmark, Thin Solid Films 401, 179 (2001)
- [64] M.Berger, L.Karlsson, S.Hogmark, Surf.Coat.Technol. 124, 253 (2000)
- [65] J.G.Ryan, S.Roberts, G.J.Slusser, Thin Solid Films, 153, 329 (1987)
- [66] J.Pelleg, G.Sade, J.Appl.Phys. 91, 6099 (2002)
- [67] L.G.Jacobsohn, F.L.Freire Jr. J.Vac.Sci.Technol. A 17, 2841 (1999)
- [68] XPS Peak Software, <http://icp.csic.es/xps/programs.html#xpspeak>
- [69] D.A.Shirley, Phys.Rev.B 5, 4709 (1972)
- [70] Y.H.Lu, Y.G.Shen, Z.F.Zhou and K.Y.Li, J.Vac.Sci.Technol. A 24, 340 (2006)
- [71] Y.H.Lu, Z.F.Zhou, P.Sit, Y.G.Shen, K.Y.Li, and Haydn Chen, Surf.Coat.Technol. 187, 98 (2004)
- [72] J.Pelleg, G.Sade, M.Sinder, D.Mogilyanski, Physica B 381, 118 (2006)

- [73] J.Ye, S.Ulrich, K.Sell, H.Leiste, M.Stüber, H.Holleck, Surf.Coat.Technol. 174-175, 959 (2003).
- [74] L.G.Jacobsohn, R.D.Averitt and M.Nastasi, J.Vac.Sci.Technol. A 21, 1639 (2003)
- [75] B.D.Cullity, Elements of X-ray diffraction, 2nd ed., Addison-Wesley (1978)
- [76] S.Q.Wang, MRS Bull. 19, 30 (1994)
- [77] R.Prioli, L.G.Jacobsohn, M.E.H.Maia da Costa and F.L.Freire Jr. Tribology Letters, 15, 177 (2003)
- [78] E.Riedo, L.Francis and H.Brune, Physical Review Letters, 88, 185505 (2002)
- [79] T.P.Mollart et.al. Surf.Coat.Technol. 86-87, 231 (1996)
- [80] L.Chaleix et.al. Surf.Coat.Technol. 91, 74 (1997)
- [81] C.Héau et.al. Surf.Coat.Technol. 116-119, 302 (1999)
- [82] C.Héau et.al. Surf.Coat.Technol. 108-109, 332 (1998)
- [83] B.Matthes et.al. Surf.Coat.Technol. 57, 97 (1993)
- [84] W.Gissler, Surf.Coat.Technol. 68-69, 556 (1994)
- [85] J.A.Tornton, S.A.E.Trans. 82, 1787 (1974)
- [86] J.Moulder, W.F.Stickle, P.E.Sobol and K.D.Bomben, Handbook of X-Ray Photoelectron Spectroscopy, Physical Electronics (1992)
- [87] Y.H.Lu et.al. Surf.Coat.Technol. 201, 1228 (2006)
- [88] M.A.Baker et.al. J.Vac.Sci.Technol. A 15(2), 284 (1997)
- [89] P.Karvankova et.al. 163-164, 149 (2003)
- [90] D.Briggs, Practical Surface Analysis, Second Edition, Wiley (1996)
- [91] R.N.Wenzel, Indust.Engen.Chem. 28, 988 (1936)
- [92] Z.J.Liu, Y.H.Lu and Y.G.Shen, J.Mater.Res. 21, 82 (2006)